

Notice of References Cited	Application/Control No. 10/766,246		Applicant(s)/Patent Under Reexamination NIELSEN ET AL.	
	Examiner HIEU HOANG		Art Unit 2452	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,438,553	08-2002	Yamada, Kazuo	1/1
*	B	US-5,963,911	10-1999	Walker et al.	705/7.12
*	C	US-6,373,585	04-2002	Mastie et al.	358/1.15
*	D	US-2003/0126464	07-2003	McDaniel et al.	713/201
*	E	US-2004/0261055	12-2004	Bertelrud et al.	717/106
*	F	US-2002/0029272	03-2002	Weller, Scott	709/226
*	G	US-6,963,897	11-2005	Hubbard, Edward A.	709/201
*	H	US-2002/0129081	09-2002	Rai et al.	709/102
*	I	US-2003/0161327	08-2003	Vlodavsky et al.	370/395.52
*	J	US-2005/0102676	05-2005	Forrester, Jason D.	718/105
*	K	US-7,062,571	06-2006	Dale et al.	709/239
*	L	US-6,748,414	06-2004	Bournas, Redha M.	718/105
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.